MAY 1972 - REVISED MARCH 1988

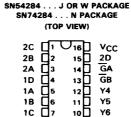
- Fast Multiplication of Two Binary Numbers
 8-Bit Product in 40 ns Typical
- Expandable for N-Bit-by-n-Bit Applications:
 16-Bit Product in 70 ns Typical
 32-Bit Product in 103 ns Typical
- Fully Compatible with Most TTL Circuits
- Diode-Clamped Inputs Simplify System Design

description

These high-speed TTL circuits are designed to be used in high-performance parallel multiplication applications. When connected as shown in Figure A, these circuits perform the positive-logic multiplication of two 4-bit binary words. The eight-bit binary product is generated with typically only 40 nanoseconds delay.

This basic four-by-four multiplier can be utilized as a fundamental building block for implementing larger multipliers. For example, the four-by-four building blocks can be connected as shown in Figure B to generate submultiple partial products. These results can then be summed in a Wallace tree, and, as illustrated, will produce a 16-bit product for the two eight-bit words typically in 70 nanoseconds. SN54H183/SN74H183 carry-save adders and SN54S181/SN74S181 rithmetic logic units with the SN54S182/SN74S182 look-ahead generator are used to achieve this high performance. The scheme is expandable for implementing N × M bit multipliers.

The SN54284 and SN54285 are characterized for operation over the full military temperature range of -55°C to 125°C; the SN74284 and SN74285 are characterized for operation from 0°C to 70°C.



SN54285 . . . J OR W PACKAGE SN74285 . . . N PACKAGE (TOP VIEW)

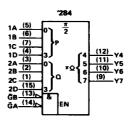
GND

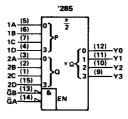
9 🗌

Y7

2C	ď٦	$ abla_{i0}$	Vcc
2B		15	2D
2A	Пз	14[]	ĞΑ
1D	□4	13 🛛	GB
1A	Дъ	12	Y0
1B	□6	11	Y1
1C	Ū٦	10 🗍	Y2
GND	[]8	9 🗍	Y3

logic symbols†





[†]These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

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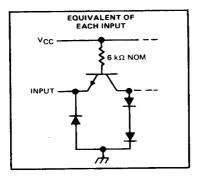


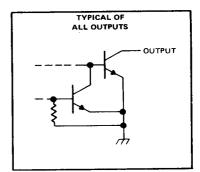
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2

TI Devices

schematics





2

BINARY INPUTS

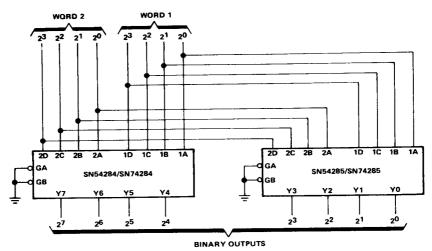
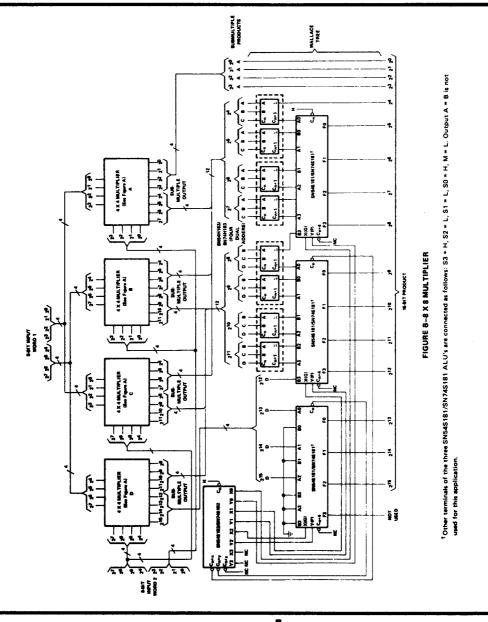


FIGURE A-4 X 4 MULTIPLIER





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)			 	. 7 V
Input voltage, VCC (see Note 1)				. 5.5 V
Storage temperature range	SN/4 Circu	115	 -65°C	to 150°C
Storage temperature range			 . ,	

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

	· · · · · · · · · · · · · · · · · · ·	SN54284 SN54285			SN74284 SN74285		
	MIN	NOM	MAX	MIN	NOM	MAX	_
	4.5	5	5.5	4.75	5	5.25	l v
Supply voltage, V _{CC}			5.5			5.5	T v
High-level output voltage, VOH			16	 		16	mA
Low-level output current, IQL	-55		125	1		70	°c
Operating free-air temperature, TA			125				

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS†	MIN	TYP‡	MAX	UNI
			2			V
VIH.	High-level input voltage				0.8	V
VIL	Low-level input voltage	14 1411 L = 12 mA	\rightarrow		-1.5	\vdash_{∇}
<u> </u>	Input clamp voltage	V _{CC} = MIN, I _I = -12 mA	+			+-
IOH High-level output current		V _{CC} = MIN, V _{IH} = 2 V,	ļ	40	40	μΑ
	High-level output current	V _{IL} = 0.8 V, V _{OH} = 5.5 V				↓_
VOL Low-level output voltage		VCC = MIN, IOL = 12 mA			0.4	1
	V _{IH} = 2 V,				1 ×	
	VIL = 0.8 V IOL = 16 mA	- 1		0.45	<u> </u>	
	VCC = MAX, VI = 5.5 V			1	m	
1	Input current at maximum input voltage	""	+		40	μ/
IH.	High-level input current	V _{CC} = MAX, V _I = 2.4 V			-1	m
IL.	Low-level input current	V _{CC} = MAX, V ₁ = 0.4 V				+
ICC Supply current		VCC = MAX, SN54284, SN542	85			
	T _A = 125°C, N package only			99		
	See Note 2				- mA	
	Supply current	VCC = MAX, SN54284, SN542	85	92	110	4
		See Note 2 SN74284, SN74	85	92	130	1

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable device type

switching characteristics, VCC = 5 V, TA = 25°C

TEST CONDITIONS	MIN	TYP	MAX	UNIT
C ₁ = 30 pF to GND,		20	30	ns
		20	30	113
		40	60	ns
		40	60	1 "`
	TEST CONDITIONS $C_L = 30 \text{ pF to GND},$ $R_{L1} = 300 \Omega \text{ to VCC},$ $R_{L2} = 600 \Omega \text{ to GND},$ See Note 3	C _L = 30 pF to GND, R _{L1} = 300 Ω to V _{CC} , R _{L2} = 600 Ω to GND,	CL = 30 pF to GND. 20 RL1 = 300 Ω to VCC. 20 RL2 = 600 Ω to GND, 40	C _L = 30 pF to GND. 20 30 R _{L1} = 300 Ω to VCC. 20 30 R _{L2} = 600 Ω to GND, 40 60

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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 $[\]ddagger_{All\ typical\ values\ are\ at\ V_{CC}}$ = 5 V, \top_{A} = 25°C.

NOTE 2: With outputs open and both enable inputs grounded, I_{CC} is measured first by selecting an output product which contains three or more high-level bits, then by selecting an output product which contains four low-level bits.

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